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|  |      | Application Number       | 10/823,385        |
|  |      | Filing Date              | April 12, 2004    |
|  |      | First Named Inventor     | James D. Earthman |
|  |      | Art Unit                 | 2877              |
|  |      | Examiner Name            |                   |
| Sheet 2  | of 2 | Attorney Docket Number   | 9804-10           |

| NON PATENT LITERATURE DOCUMENTS |                       |   |                |
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| Examiner Initials*              | Cite No. <sup>1</sup> | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published. | T <sup>2</sup> |
| SN                              | AB                    | BREDE ET AL., "Brittle Crack Propagation in Silicon Single Crystals," J. Appl. Phys., Vol. 70, No. 2, 15 July 1991, pp. 758-71.   |                |
| SN                              | AC                    | BUERKLE ET AL., "Rapid Defect Detection by Laser Light Scattering," Materials Evaluation, June 1992, pp. 670-77.  |                |
| SN                              | AD                    | DIAZ ET AL., "Optical Measurement of the Plastic Zone Size in a Notched ...," Optics and Lasers in Engineering, Vol. 35, 2001, pp. 325-33.  |                |
| SN                              | AE                    | VALLIANT ET AL., "Instrument for On-line Monitoring of Surface ...," Opt. Eng., Vol. 39, No. 12, December 2000, pp. 3247-54.  |                |
| SN                              | AF                    | ZHAO ET AL., "Characterization of Pitting Corrosion in Aluminum ...," Applied Physics Letters, Vol. 73, No. 17, 26 October 1998, pp. 2432-34.   |                |
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| Examiner Signature | /Sang Nguyen/ | Date Considered | 07/24/2006 |
|--------------------|---------------|-----------------|------------|

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